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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

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In re application of: Eric Teh Gim Aik

Attorney Docket No.: ALTRP085/ A880

Application No.: Please assign

Examiner: Not yet assigned

Filed: Herewith

Group: Not Yet Assigned

**Title: ELECTRICAL DESIGN RULE  
CHECKING EXPERT TRAVERSER SYSTEM**

**CERTIFICATE OF MAILING**

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first-class mail on June 19, 2003 in an envelope addressed to the Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450.

Signed: \_\_\_\_\_



Ryan Eachus

**INFORMATION DISCLOSURE STATEMENT  
37 CFR §§1.56 AND 1.97(b)**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

The references listed in the attached PTO Form 1449, copies of which are attached, may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§1.56 and 1.97. The Examiner is requested to make these references of official record in this application.

This Information Disclosure Statement is: (i) filed within three (3) months of the filing date of the above-referenced application, (ii) believed to be filed before the mailing date of a first Office Action on the merits, or (iii) believed to be filed before the mailing of a first Office Action after the filing of a Request for Continued Examination under §1.114. Accordingly, it is believed that no fees are due in connection with the filing of this Information Disclosure Statement. However, if it is determined that any fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 500388 (Order No. ALTRP085).

Respectfully submitted,  
BEYER WEAVER & THOMAS, LLP



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<b>Form 1449 (Modified)</b>				Atty Docket No. ALTRP085/ A880	Application No.: Please assign		
<b>Information Disclosure Statement By Applicant</b>				Applicant: Eric Teh Gim Aik			
(Use Several Sheets if Necessary)				Filing Date Herewith	Group Please assign		

### U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
	B						

### Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	C							
	D							
	E							

### Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	F	<a href="http://biz.yahoo.com/bw/020130/300146_1.html">http://biz.yahoo.com/bw/020130/300146_1.html</a> - Page no longer available
	G	Using Electric 9-2: Design-Rule Checking, <a href="http://www.staticfreesoft.com/manual/text/chap09-02.html">http://www.staticfreesoft.com/manual/text/chap09-02.html</a>
	H	Robert N. Mayo, Magic Tutorial #6: Design-Rule Checking, <a href="http://infopad.eecs.berkeley.edu/~icdesign/magic/tut6.html">http://infopad.eecs.berkeley.edu/~icdesign/magic/tut6.html</a>
	I	Celebrity IC Design and Verification Software, SILVACO International. <a href="http://www.silvaco.com/products/legacy/celebrity/celebrity.pdf">http://www.silvaco.com/products/legacy/celebrity/celebrity.pdf</a>
	J	CyberCut A Network Manufacturing Service, Design Rule Checking. <a href="http://cybercut.berkeley.edu/html/research/project_rule_checker.htm">http://cybercut.berkeley.edu/html/research/project_rule_checker.htm</a>
	K	Randall et al., Design Rule Checking and Pattern Processing for Advanced MEMS Designs <a href="http://www1.zyvex.com/TEXMEMS3/Abstracts/JRandall.html">http://www1.zyvex.com/TEXMEMS3/Abstracts/JRandall.html</a>
	L	P3 Design Rule Checker, Hierarchical and Incremental Design Rule Checker, <a href="http://www.phase3.com/p3v-dsnchk.htm">http://www.phase3.com/p3v-dsnchk.htm</a>
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.